





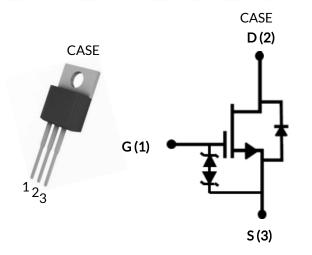








UF3C065080T3S



Part Number	Package	Marking
UF3C065080T3S	TO-220-3L	UF3C065080T3S









$650V-80m\Omega$ SiC Cascode

Rev. A. June 2019

Description

United Silicon Carbide's cascode products co-package its high-performance G3 SiC JFETs with a cascode optimized MOSFET to produce the only standard gate drive SiC device in the market today. This series exhibits ultra-low gate charge, but also the best reverse recovery characteristics of any device of similar ratings. These devices are excellent for switching inductive loads when used with recommended RC-snubbers, and any application requiring standard gate drive.

Features

- Typical on-resistance R_{DS(on),typ} of 80mΩ
- Maximum operating temperature of 175°C
- Excellent reverse recovery
- Low gate charge
- Low intrinsic capacitance
- ESD protected, HBM class 2
- Very low switching losses (required RC-snubber loss negligible under typical operating conditions)

Typical applications

- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating













Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		650	V
Gate-source voltage	V_{GS}	DC	-25 to +25	V
Continuous drain current ¹	I _D	T _C = 25°C	31	Α
		T _C = 100°C	23	Α
Pulsed drain current ²	I _{DM}	T _C = 25°C	65	Α
Single pulsed avalanche energy ³	E _{AS}	L=15mH, I _{AS} =2.1A	33	mJ
Power dissipation	P _{tot}	T _C = 25°C	190	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J,T_STG		-55 to 175	°C
Max. lead temperature for soldering, 1/8" from case for 5 seconds	T _L		250	°C

- 1. Limited by $T_{J,\text{max}}$
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	Offics
Thermal resistance, junction-to-case	$R_{ heta$ JC			0.61	0.79	°C/W













Electrical Characteristics (T_J = +25°C unless otherwise specified)

Typical Performance - Static

Parameter	Symbol	Test Conditions		Units			
			Min	Тур	Max	UIIILS	
Drain-source breakdown voltage	BV _{DS}	$V_{GS}=0V, I_D=1mA$	650			V	
Total drain leakage current	I _{DSS}	V _{DS} =650V, V _{GS} =0V, T _J =25°C		6	100	^	
		V _{DS} =650V, V _{GS} =0V, T _J =175°C		40		- μΑ	
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C, V _{GS} =-20V / +20V		6	±20	μΑ	
Drain-source on-resistance	R _{DS(on)}	V_{GS} =12V, I_D =20A, T_J =25°C		80	100	mΩ	
		V _{GS} =12V, I _D =20A, T _J =175°C		141		11122	
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_D =10mA	4	5	6	V	
Gate resistance	R_{G}	f=1MHz, open drain		4.5		Ω	

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions		Units		
			Min	Тур	Max	Units
Diode continuous forward current ¹	I _S	T _C =25°C			31	Α
Diode pulse current ²	I _{S,pulse}	T _C =25°C			65	Α
Forward voltage	V_{FSD}	V _{GS} =0V, I _F =10A, T _J =25°C		1.5	2	_ V
		V _{GS} =0V, I _F =10A, T _J =175°C		1.75		
Reverse recovery charge	Q _{rr}	V_R =400V, I_F =20A, V_{GS} =-5V, R_{G_EXT} =10 Ω		119		nC
Reverse recovery time	t _{rr}	di/dt=2200A/μs, T _J =25°C		16		ns
Reverse recovery charge	Q _{rr}	V_R =400V, I_F =20A, V_{GS} =-5V, R_{G_EXT} =10 Ω		73		nC
Reverse recovery time	t _{rr}	di/dt=2200A/μs, Τ _J =150°C		11		ns













Typical Performance - Dynamic

Parameter	Symbol	Test Conditions	Value			l laite
		Test Conditions -	Min	Тур	Max	Units
Input capacitance	C _{iss}	\/ -100\/ \/ -0\/		1500		
Output capacitance	C _{oss}	- V _{DS} =100V, V _{GS} =0V - f=100kHz		104		pF
Reverse transfer capacitance	C_{rss}	1-100KH2		2.6		
Effective output capacitance, energy related	C _{oss(er)}	V _{DS} =0V to 400V, V _{GS} =0V		77		pF
Effective output capacitance, time related	C _{oss(tr)}	V _{DS} =0V to 400V, V _{GS} =0V		176		pF
C _{OSS} stored energy	E _{oss}	V _{DS} =400V, V _{GS} =0V		6.2		μЈ
Total gate charge	Q_{G}	V _{DS} =400V, I _D =20A,		51		
Gate-drain charge	Q_{GD}	$V_{GS} = -5V \text{ to } 15V$		11		nC
Gate-source charge	Q_{GS}	VGS - 3V 1013V		19		
Turn-on delay time	$t_{d(on)}$			25		- ns
Rise time	t _r	V_{DS} =400V, I_D =20A, Gate		14		
Turn-off delay time	$t_{d(off)}$	Driver =-5V to +15V, Turn-on $R_{G,EXT}$ =1 Ω ,		54		
Fall time	t _f	Turn-off $R_{G,EXT}$ = 22 Ω		11		
Turn-on energy including R _S energy ⁴	E _{ON}	Inductive Load,		182		μ
Turn-off energy including R _S energy ⁴	E _{OFF}	FWD: same device with $V_{GS} = -5V$ and $R_G = 22\Omega$, RC snubber: $R_S = 5\Omega$ and $C_S = 100 pF$, $T_J = 25^{\circ}C$		24		
Total switching energy including R _s energy ⁴	E _{TOTAL}			206		
Snubber R _S energy during turn-on	E _{RS_ON}			0.6		
Snubber R _S energy during turn-off	E _{RS_OFF}			1.1		
Turn-on delay time	t _{d(on)}			22		ns
Rise time	t _r	$V_{DS}=400V, I_D=20A, Gate$ $Driver =-5V to +15V,$ $Turn-on R_{G,EXT}=1\Omega,$ $Turn-off R_{G,EXT}=22\Omega$ $Inductive Load,$ $FWD: same device with$ $V_{GS}=-5V \text{ and } R_G=22\Omega,$ $RC \text{ snubber: } R_S=5\Omega \text{ and}$ $C_S=100pF,$ $T_J=150°C$		14		
Turn-off delay time	t _{d(off)}			55		
Fall time	t _f			12		
Turn-on energy including R _S energy ⁴	E _{ON}			156		
Turn-off energy including R _S energy ⁴	E _{OFF}			25		
Total switching energy including R _S energy ⁴	E _{TOTAL}			181		μЈ
Snubber R _S energy during turn-on	E _{RS_ON}			0.6		
Snubber R _S energy during turn-off	E _{RS_OFF}			1.2		

^{4.} The switching performance are evaluated with a RC snubber circuit as shown in Figure 24.





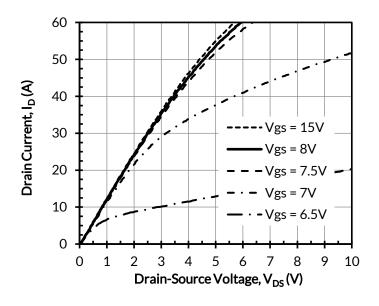








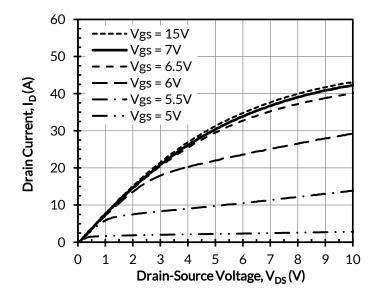
Typical Performance Diagrams



60 50 Drain Current, I_D (A) 40 30 Vgs = 15V Vgs = 8V 20 - Vgs = 7V - Vgs = 6.5V 10 - Vgs = 6V 0 0 1 2 3 5 6 10 Drain-Source Voltage, V_{DS} (V)

Figure 1. Typical output characteristics at T_J = - 55°C, t_p < 250 μ s

Figure 2. Typical output characteristics at T_J = 25°C, t_p < 250 μ s



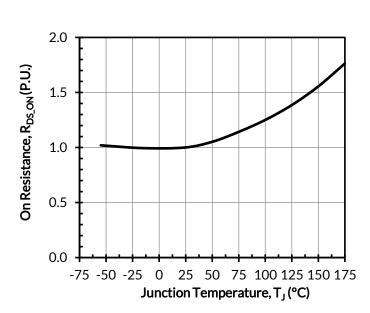


Figure 3. Typical output characteristics at T_J = 175°C, t_p < 250 μs

Figure 4. Normalized on-resistance vs. temperature at V_{GS} = 12V and I_D = 20A



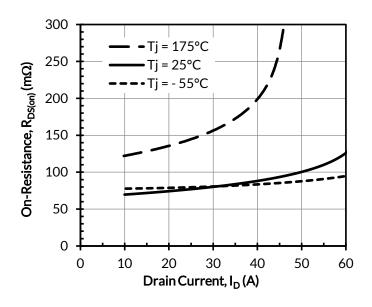












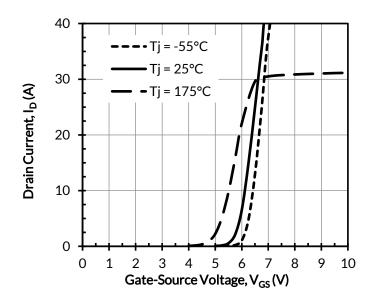
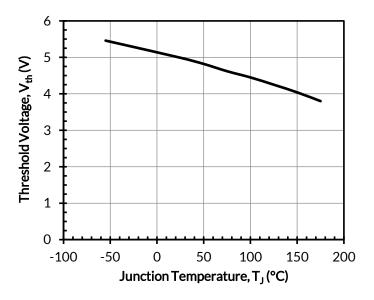


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at V_{DS} = 5V



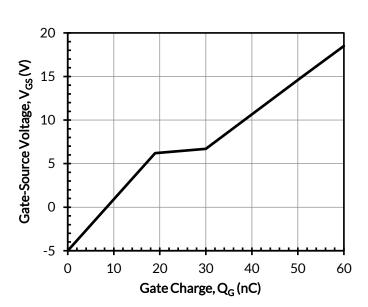


Figure 7. Threshold voltage vs. junction temperature at V_{DS} = 5V and I_{D} = 10mA

Figure 8. Typical gate charge at V_{DS} = 400V and I_{D} = 20A













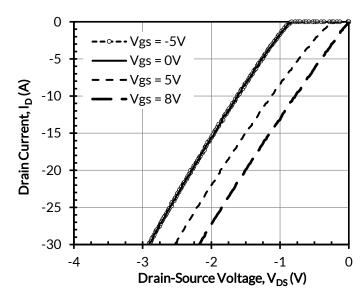


Figure 9. 3rd quadrant characteristics at $T_J = -55^{\circ}C$

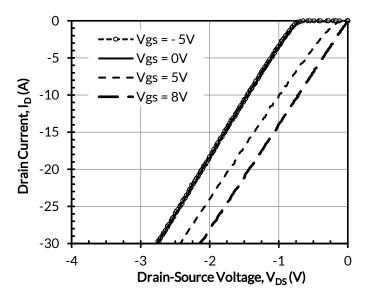


Figure 10. 3rd quadrant characteristics at $T_J = 25$ °C

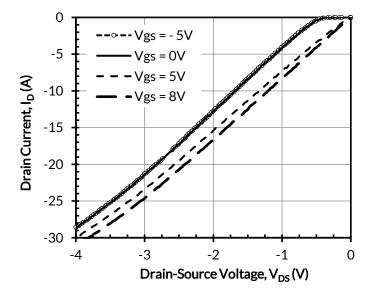


Figure 11. 3rd quadrant characteristics at $T_J = 175$ °C

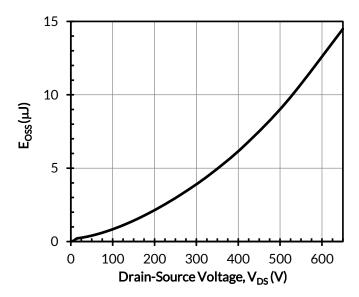


Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$



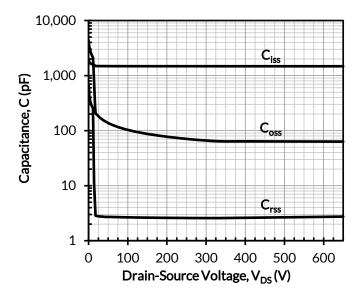








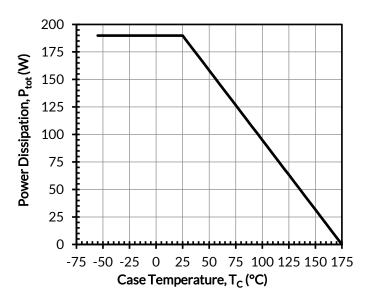




35 30 25 20 15 10 -75 -50 -25 0 25 50 75 100 125 150 175 Case Temperature, T_c (°C)

Figure 13. Typical capacitances at f = 100kHz and $V_{GS} = 0V$

Figure 14. DC drain current derating



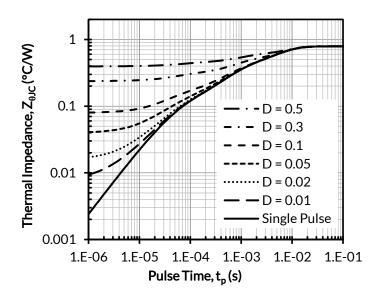


Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance



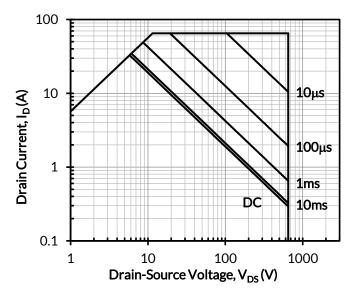








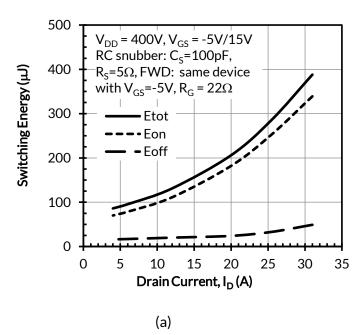




140 120 100 Qrr (nC) 80 60 $V_{DD} = 400V, I_{S} = 20A,$ $di/dt = 2200A/\mu s$, 40 $V_{GS} = -5V$, $R_G = 10\Omega$ 20 0 25 50 75 100 125 150 175 0 Junction Temperature, T_J (°C)

Figure 17. Safe operation area at $T_C = 25$ °C, D = 0, Parameter t_p

Figure 18. Reverse recovery charge Qrr vs. junction temperture



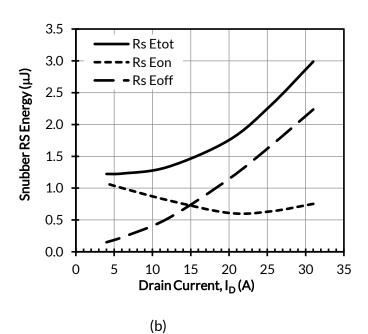


Figure 19. Clamped inductive switching energy (a) and RC snubber energy loss (b) vs. drain current at T_J = 25°C, turn-on R_{G_EXT} = 1Ω , and turn-off R_{G_EXT} = 22Ω



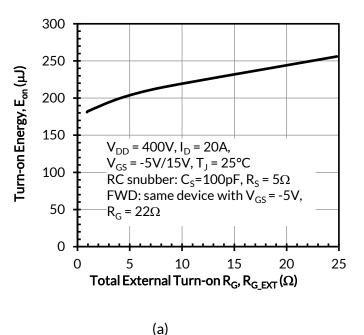












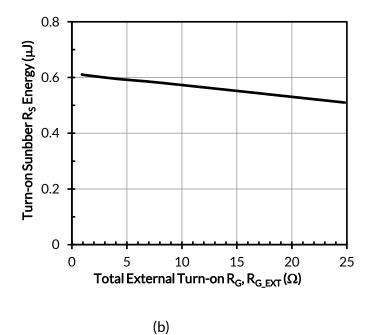
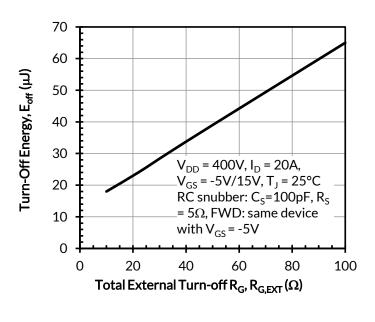
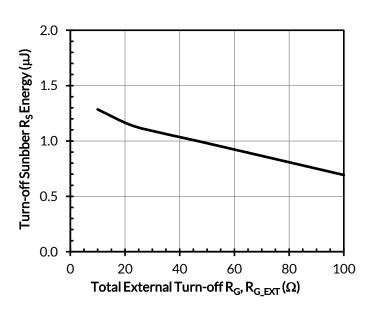


Figure 20. Clamped inductive switching turn-on energy including RC snubber energy loss (a) and RC snubber energy loss (b) as a function of total external turn-on gate resistor R_{G_EXT}



(a)



(b)

Figure 21. Clamped inductive switching turn-off energy including RC snubber energy loss (a) and RC snubber energy loss (b) as a function of total external turn-off gate resistor $R_{G EXT}$



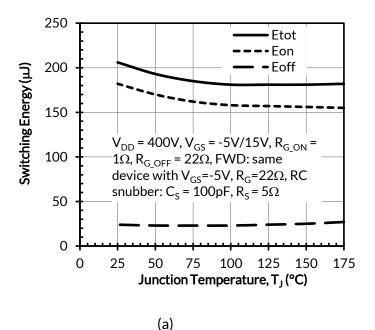












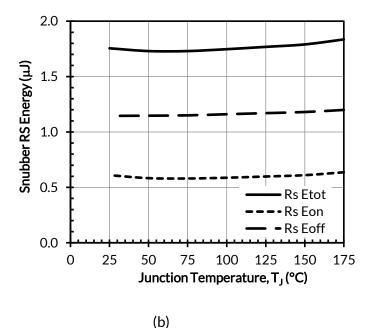
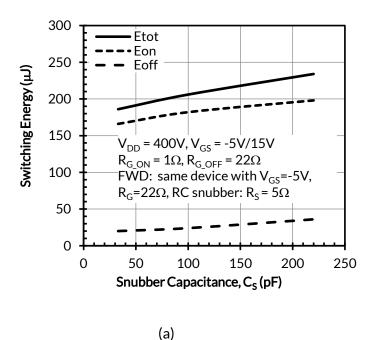


Figure 22. Clamped inductive switching energy including RC snubber energy loss (a) and RC snubber energy loss (b) as a function of junction temperature at $I_D = 20A$



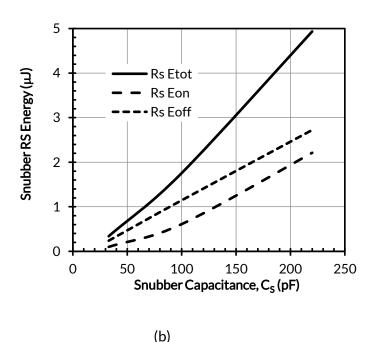


Figure 23. Clamped inductive switching energy including RC snubber energy loss (a) and RC snubber energy loss (b) as a function of snubber capacitance at I_D = 20A and T_J = 25°C













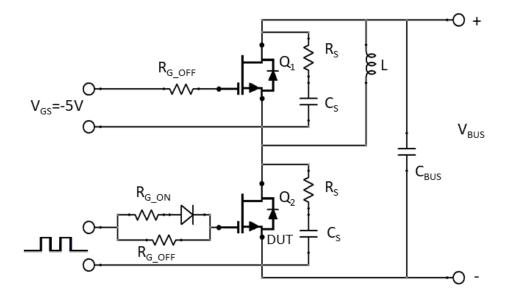


Figure 24. Clamped inductive load switching test circuit An RC snubber ($R_S = 5\Omega$ and $C_S = 100$ pF) is required to improve the turn-off waveforms.

Applications Information

SiC cascodes are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_T) leading to low conduction and switching losses. The SiC cascodes also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode.

Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the cascode is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on cascode operation, see www.unitedsic.com.

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